

Rev A

## 3 mm Micro MATE-N-LOK\* Connector

## 1. INTRODUCTION

#### 1.1 Purpose

Testing was performed on 3 mm Micro MATE-N-LOK\* Connectors to determine its conformance related to the requirements of product specification 108-1836 Rev.E.

#### 1.2 Scope

This report covers the electrical, mechanical, and environmental performance of 3 mm Micro MATE-N-LOK\* Connectors. Testing was performed at the Shanghai Electrical Components Test Laboratory between May 29, 2018 and Aug.24, 2018. The associated test number is TP-18-01416.

#### 1.3 Conclusion

Based on the test results, all meet the requirement.

#### 1.4 Test Specimens

Specimens with the following part numbers as Table 1 were used for test, all wired specimens used 22AWG and 20AWG wire.

Туре	Part No	Description	Qty.	Comments		
	2315752-4	RECEPTACLE HOUSING, SINGLE ROW, MICRO MATE-N-LOK	/			
1	2315785-4	PLUG HOUSING, SINGLE ROW, FREE HANGING MICRO MATE-N-LOK	5 pairs/group			
2	2315752-4	RECEPTACLE HOUSING, SINGLE ROW, MICRO MATE-N-LOK	E poiro/group	Only 2315752-4, 2315785-4, 3-		
2	2315786-4	PLUG HOUSING, SINGLE ROW, PANEL MOUNT, MICRO MATE-N-LOK	5 pairs/group	794617-0 and 3- 794615-0 are		
2	3-794617-0	RECEPTACLE HOUSING, 2 TO 24 POSITION, DUAL ROW, MICRO MATE-N-LOK	E poiro/group	required to do group 5 test (glow wire test), and		
3	3-794615-0	PLUG HOUSING, 2 TO 24 POSITION DUAL ROW, PANEL MOUNT, MICRO MATE-N-LOK	5 pairs/group	2pcs/part no. for this test.		
	3-794617-0	RECEPTACLE HOUSING, 2 TO 24 POSITION, DUAL ROW, MICRO MATE-N-LOK	E poiro/group			
4	3-794616-0	PLUG HOUSING, 2 TO 24 POSITION DUAL ROW, FREE HANGING, MICRO MATE-N-LOK	5 pairs/group			



#### 1.5 Test Sequence

	Table 2							
	Test Group							
Test	1	2	3	4	5			
		T	est Sequenc	e	•			
Examination of Product	1,9	1,8	1,8	1	1			
Termination resistance	3,7	2,6						
Insulation resistance			2,6					
Dielectric withstanding			3,7					
Temperature rise vs current		3,7						
Temperature rise								
Vibration, random	5							
Mechanical shock	6							
Durability	4	2						
Mating force	2		2					
Unmating force	8							
Housing lock strength				5				
Thermal shock			4	3				
Humidity/temperature cycling			5	4				
Temperature life		5						
Mixed flowing gas		4						
Crimp contact retention			9					
Glow wire end-products test					2			
Crimp contact insertion force				2				

Note:

a). Test group defined per customer requirement

b). Numbers indicate sequence in which tests are performed.

#### 1.6 Environmental Conditions

Unless otherwise stated, the following environmental conditions prevailed during testing:Temperature:15°C to 35°CRelative Humidity:25% to 75%

## 2. TEST PROCEDUES

#### 2.1. Examination of Product

Visual Inspection: appearance, and function of specimens pursuant to the applicable inspection plan. Requirements: Meets requirements of product drawing and no physical damage. Test Method: EIA-364-18 B

#### 2.2. Termination resistance

Subject specimens to 100 milliamperes maximum and 20 millivolts maximum open circuit voltage. Requirements: 20 m $\Omega$  Max. Test Method: IEC 60512-2-1-2002



#### 2.3. Insulation Resistance

Test between adjacent contacts of mated specimens with 500 V DC for 2 minutes. Requirements: 1000M $\Omega$ . Min (initial); 500M $\Omega$ . Min (final) Test Method: EIA-364-21E

#### 2.4. Dielectric withstanding

1500 volts AC at sea level. Test between adjacent contacts of mated specimens. 1 minute hold with no breakdown, flashover, or 0.5 milliampere maximum leakage. Requirements: No breakdown or flashover. Test Method: EIA-364-20D

#### 2.5. Temperature rise

Stabilize at a single current level until 3 readings at 5 minute intervals are within 1°C. Test current: 5A DC for 4 Pos. 4.25A DC for 10 Pos. All wired specimens used 20 AWG wire for this group.

Requirements: 30 °C Max.

Test Method: EIA-364-70C, Method 1.

#### 2.6. Vibration, random

Subject mated specimens to 3.10 G's rms between 20-500 Hz. 15 minutes in each of 3 mutually perpendicular planes. Requirements: No discontinuities of 1 microsecond or longer duration. Test Method: EIA-364-28F, Test Condition VII, Condition D

#### 2.7. Mechanical shock

Subject mated specimens to 50 G's half-sine shock pulses of 11 milliseconds duration. 3 shocks in each direction applied along 3 mutually perpendicular planes, 18total shocks. Requirements: No discontinuities of 1 microsecond or longer duration. Test Method: EIA-364-27C, Method A

#### 2.8. Durability

Mate and unmate specimens for 30 cycles for tin plated specimens, 75 cycles for 15 µin gold plated specimens, and 150 cycles for 30 µin gold plated specimens at a maximum rate of 500 cycles per hour. Requirements: no physical damage. Test Method: EIA-364-9C

#### 2.9. Mating force&unmating

Measure the force necessary to mate and unmate sampels with a rate of 5.08 mm /min. Requirements: Mating fore 4 Pos. 27.44 N Max.(0.7kgf\*4\*9.8=27.44N, 0.7kgf Max. per contact); 10 Pos. 68.60 N Max.(0.7kgf\*10\*9.8=68.60, 0.7kgf Max. per contact); Unmating force 4 Pos. 2.74 N Min. (0.07kgf\*4\*9.8=2.74N, 0.07kgf Min. per contact); 10 Pos. 6.86 N Min. (0.07kgf\*10\*9.8=6.86N, 0.07kgf Min. per contact); Test Method: EIA-364-13E-2011

#### 2.10. Housing Locking Strength

Determine housing lock strength at a maximum rate of 12.7 mm per minute. Requirements: 26.46 N Min. Test Method: EIA-364-98-1997

## 2.11. Thermal shock

Mated connector -40°C/30 min., 105°C/30 min. Making this a cycle, repeat 5 cycles. Requirements: No physical damage. Test Method: EIA-364-32G



#### 2.12. Humidity/temperature cycling

Subject specimens to 10 cycles (10 days) between 25 and 65°C at 80 to 100% RH. Requirements: No visible defects or deviations, no cracks on the isolating parts. Test Method: EIA-364-31E-2017, Method III.

#### 2.13. Temperature life

Subject mated specimens to 105°C for 500 hours. Requirements: No visible defects or deviations, no cracks on the isolating parts. Test Method: EIA-364-17C, Method A.

#### 2.14. Mixed flowing gas

Subject mated specimens to environmental Class IIA for 20 days (30°C and 70%R.H., Cl<sub>2</sub> 10ppb, NO<sub>2</sub> 200ppb, H<sub>2</sub>S 10ppb, SO<sub>2</sub> 100ppb). Requirements: No physical damage, and meet requirement of subsequent test. Test Method: EIA-364-65, Class IIA.

#### 2.15. Crimp contact retention

Apply an axial load of 1.81 kgf to contacts at a rate of 0.45 kgf per second and hold for 6 seconds. Requirements: Contact shall not dislodge. Test Method: EIA-364-29C.

#### 2.16. Glow wire end-products test

The extremity of the wire is positioned horizontally and brought into contact with the sample with a force between 0.85 and 1.2N for a period of 30s. Test temperature:  $750^{\circ}$  Time of Glow tip application Ta: 30s Requirements: Te-Ti <2s or no flame Test Method: IEC 60335-1 edition 5.2 2016-05.

#### 2.17. Crimp contact insertion force

Measure force necessary to insert crimped contacts into housing. Requirements: 6.86 N Max. Test Method: 108-1836 Rev.E.

#### 3. SUMMARY OF TESTING

Crown	Test Item	QTY	Condition	Test Result				Paguiromont	Conclusion
Group		QII	Condition	Max	Min	Ave	Unit	Requirement	Conclusion
	Examination of Product	20	initial	No phys	No physical damage occurred			No abnormalities	Meet spec
		5	Initial-type1	17.88	13.19	14.46	Ν	27.44 N Max.	Meet spec
	Mating force	5	Initial-type2	25.26	11.91	18.89	1N = 27.44 IN IVIA)	27.44 N Wax.	
	Mating force	5	Initial-type3	46.16	32.84	37.33	N 68.60 N Max.	68.60 N Max.	
		5	Initial-type4	39.04	26.01	32.97	IN	00.00 IN Max.	
	Termination resistance	5	Initial-type1	5.37	3.66	4.24	mΩ 2	20 mΩ Max.	Meet spec
		5	Initial-type2	9.23	5.18	7.21			
		5	Initial-type3	6.85	3.85	4.53			
1		5	Initial-type4	5.28	3.79	4.56			
	Durability	20	final	No physical damage occurred			/	No abnormalities	Meet spec
	Vibration, random	20	final	No physical damage, no electrical discontinuity greater than 1 μs			/	No abnormalities	Meet spec
	Mechanical shock	20	final	No physical damage, no electrical discontinuity greater than 1 µs		/	No abnormalities	Meet spec	
	Termination resistance	5	final-type1	14.10	4.22	7.82	- mΩ 20 mΩ Max.		
		5	final-type2	16.58	4.74	10.09		Meet spec	
		5	final-type3	11.73	4.09	5.99			
		5	final-type4	13.93	4.19	6.95			



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-	<b>-</b>		Condition	Test Result					<u> </u>
Group	Test Item	QTY		Max	Min	Ave	Unit	Requirement	Conclusion
		5	final-type1	8.88	7.91	7.34	N		Maatanaa
	I Inmoting force	5	final-type2	3.63	3.01	3.20	N 2.	2.74 N Min.	
	Unmating force	5	final-type3	13.06	10.06	12.08	N	6.86 N Min.	Meet spec
		5	final-type4	14.97	10.28	12.52	IN	0.00 N WIIII.	
	Examination of Product	20	final	No physi	cal damage	occurred	/	No abnormalities	Meet spec
	Examination of Product	20	initial	No physical damage occurred.		/	No abnormalities	Meet spec	
		5	Initial-type1	4.89	3.63	4.14	_		
	Termination resistance	5	Initial-type2	4.75	4.75	3.89	mΩ	20 mΩ Max.	Meet spec
		5	Initial-type3	5.30	2.54	4.23		20	meetepee
		5	Initial-type4	5.50	3.41	4.25			
		5	Initial-type1	20.22	15.55	18.00	_		
	Temperature rise vs	5	Initial-type2	19.55	13.84	16.40	°C	30 °C Max.	Meet spec
	current	5	Initial-type3	23.18	19.39	21.09	-	00 0 Max.	moor op oo
		5	Initial-type4	23.99	19.13	21.47			
2	Mixed flowing gas	20	final	No physi	No physical damage occurred		/	No abnormalities	Meet spec
L	Temperature life	20	final		cal damage		/	No abnormalities	Meet spec
		5	final-type1	7.67	3.86	5.20	mΩ	20 mΩ Max.	Meet spec
	Termination resistance	5	final-type2	8.05	4.21	5.53			
		5	final-type3	7.59	4.16	5.14	11132		
		5	final-type4	8.30	4.26	5.24			
	Temperature rise vs current	5	final-type1	22.31	16.60	18.98			
		5	final-type2	23.77	18.14	20.23	°C	30 °C Max.	Meet spec
		5	final-type3	25.11	20.20	22.54		SU C Max.	weet spec
		5	final-type4	23.97	20.49	22.04			
	Examination of Product	20	final	No physical damage occurred		/	No abnormalities	Meet spec	
	Examination of Product	20	initial	No physical damage occurred			/	No abnormalities	Meet spec
	Crimp contact insertion force	5	Initial-type1	5.33	1.27	3.32			
		5	Initial-type2	5.73	1.07	3.49	N 6.86 N Max.	Moot spoo	
		5	Initial-type3	5.54	1.39	3.52		0.00 N Max.	Meet spec
		5	Initial-type4	5.42	1.60	3.58			
		5	Initial-type1	3.73	0.55	1.45			
	Insulation resistance	5	Initial-type2	1.66	0.54	1.12	10 <sup>11</sup> Ω	1000 MΩ Min.	Meet spec
		5	Initial-type3	1.57	0.60	0.97	10 32		Weet spec
		5	Initial-type4	4.19	0.73	0.97			
	Dielectric withstanding	20	initial	No brea	kdown, no f	lashover	/	No abnormalities	Meet spec
3	Thermal shock	20	final	No physi	cal damage	occurred	/	No abnormalities	Meet spec
	Humidity/temperature cycling	20	final	No physi	cal damage	occurred	/	No abnormalities	Meet spec
		5	final-type1	4.40	1.85	3.04			
	Inculation register	5	final-type2	5.26	2.37	3.32	10 <sup>10</sup> Ω	500 140 15	Maar
	Insulation resistance	5	final-type3	4.40	1.17	1.91		500 MΩ Min.	Meet spec
		5	final-type4	3.00	1.24	1.93	]		
	Dielectric withstanding	20	final	No breakdown, no flashover			/	No abnormalities	Meet spec
	Examination of Product	20	final	No physical damage occurred			/	No abnormalities	Meet spec
	Crimp contact retention	20	final	Contact were not dislodged.		/	Contact shall not dislodge	Meet spec	



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Group	Test Item	QTY	Condition	Test Result				Requirement	Conclusion
Group	restitem	QIT		Max	Min	Ave	Unit	Requirement	Conclusion
4	Examination of Product	20	initial	No physical damage occurred			/	No abnormalities	Meet spec
	Thermal shock	20	initial	No physical damage occurred			/	No abnormalities	Meet spec
	Humidity/temperature cycling	20	final	No physical damage occurred			/	No abnormalities	Meet spec
	Housing lock strength	5	final-type1	34.02	32.58	33.28	- N	26.46 N Min	Meet spec
		5	final-type2	34.14	33.67	33.99			
		5	final-type3	32.81	30.86	32.23			
		5	final-type4	38.92	34.09	35.50			
5	Examination of Product	8	initial	No physical damage occurred		/	No abnormalities	Meet spec	
5	Glow wire end-products test	8	final	No flame			/	Te-Ti ≤2s or no flame	Meet spec

Note: 1 kgf=9.8 N; 100 M $\Omega$ =10<sup>8</sup>  $\Omega$ .

## 4. CALIBRATION

## 4.1 Calibration Statement

All equipment containing a calibration number is calibrated and traceable through TE Connectivity (TE).

## 5. VALIDATION

Requested by:	
Jyotirmaya	2018 05 18 / /
Product Engineer TE Connectivity India Pvt Ltd.	
Prepared by:	
Xuewei Liao	2018 09 14 / /
Test Engineer Shanghai Electrical Components	Test Lab.
Approved by:	
Robin Lu	2018 09 14
Manager Shanghai Electrical Components	Test Lab

Shanghai Electrical Components Test Lab.